

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination GOO ET AL.	
		Examiner Lex Malsawma	Art Unit 2823	Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,365,465 B1	04-2002	Chan et al.	438/283
	B	US-6,475,869 B1	11-2002	Yu, Bin	438/197
	C	US-6,605,498 B1	08-2003	Murthy et al.	438/197
	D	US-6,764,884 B1	07-2004	Yu et al.	438/157
	E	US-6,800,910 B2	10-2004	Lin et al.	257/410
	F	US-6,803,631 B2	10-2004	Dakshina-Murthy et al.	257/349
	G	US-6,815,738 B2	11-2004	Rim, Kern	257/256
	H	US-6,852,559 B2	02-2005	Kwak et al.	438/44
	I	US-6,855,582 B1	02-2005	Dakshina-Murthy et al.	438/157
	J	US-6,855,583 B1	02-2005	Krivokapic et al.	438/157
	K	US-6,855,989 B1	02-2005	Wang et al.	257/347
	L	US-6,885,055 B2	04-2005	Lee, Jong-Ho	257/308
	M	US-2002/0037619 A1	03-2002	Sugihara et al.	438/289

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Huang et al., "Sub 50-nm FinFET: PMOS", 1999, IEDM Technical Digest, pp. 67-70.
	V	Huang et al., "Sub-50 nm P-Channel FinFET", May 2001, IEEE Trans. on Electron Devices, pp. 880-886.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination GOO ET AL.	
		Examiner	Art Unit	Page 2 of 2
		Lex Malsawma	2823	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0178677 A1	09-2003	Clark et al.	257/347
	B	US-2003/0215184 A1	11-2003	Salib, Michael S.	385/37
	C	US-2004/0169239 A1	09-2004	Rim, Kern	257/411
	D	US-2005/0040444 A1	02-2005	Cohen, Guy Moshe	257/288
	E	US-2005/0048727 A1	03-2005	Maszara et al.	438/285
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.